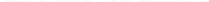


<p>Substitute for form 1449A/PTO</p> <p>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</p> <p><i>(use as many sheets as necessary)</i></p>				<p>Complete if Known</p>	
<p>Sheet</p>		<p>of</p>		<p>Application Number</p>	
				<p>Filing Date</p>	
				<p>First Named Inventor</p>	Seung Eon Moon
				<p>Art Unit</p>	
				<p>Examiner Name</p>	
				<p>Attorney Docket Number</p>	51876P400

U.S. PATENT DOCUMENTS

FOREIGN PATENT DOCUMENTS

Examiner Signature		Date Considered	3/13/04
-----------------------	---	--------------------	---------

***Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication.**

¹Applicant's unique citation designation number (optional). ²See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of reign of the Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶Applicant is to place a check mark here if English language Translation is attached.

Based on PTO/SB/08A (08-03) as modified by Blakely, Selkoff, Taylor & Zafman (w/t) 08/11/2003

Send To: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22212-1450

Information Disclosure Statement

New U.S. Patent Application for
MICROWAVE TUNABLE DEVICE HAVING
FERROELECTRIC/DIELECTRIC BST FILM
Our Ref. No.: P02EC054/US/jy

Reference No.:

- (1) KR Laid-Open No. 2001-77095 *JM*
- (2) U.S. Patent No. 5,728,603

(3) High nonlinearity of $Ba_{0.6}Sr_{0.4}TiO_3$ films heteroepitaxially
grown on MgO substrates *JM*

(Applied Physics Letters, Vol. 77 No. 16, 16 October 2000, Pages 2587-2589)

(4) Orientation dependent microwave dielectric properties of
ferroelectric $Ba_{1-x}Sr_xTiO_3$ thin films *JM*

(Applied Physics Letters, Vol. 83, No. 11, 15 September 2003, Pages 1-3)